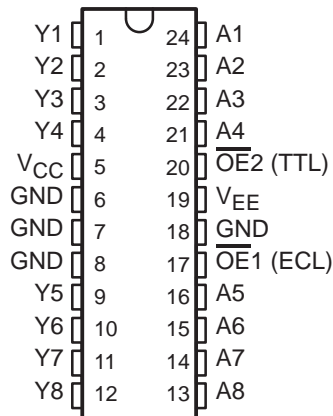


# SN100KT5541 OCTAL ECL-TO-TTL TRANSLATOR WITH 3-STATE OUTPUTS

SDZS004A – NOVEMBER 1989 – REVISED MAY 1990

- 100K Compatible
- ECL and TTL Control Inputs
- Noninverting Outputs
- Flow-Through Architecture Optimizes PCB Layout
- Center Pin  $V_{CC}$ ,  $V_{EE}$ , and GND Configurations Minimize High-Speed Switching Noise
- Package Options Include “Small Outline” Packages and Standard Plastic 300-mil DIPs

DW OR NT PACKAGE  
(TOP VIEW)



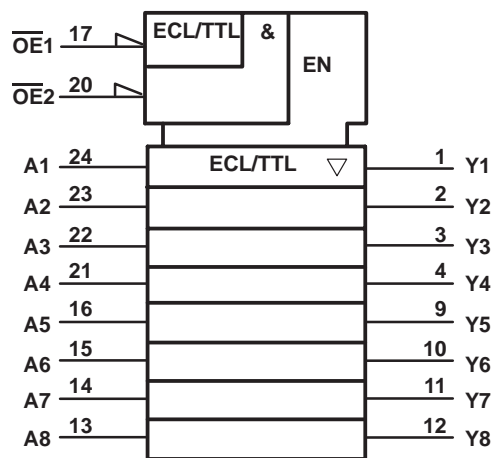
## description

This octal ECL-to-TTL translator is designed to provide a efficient translation between a 100K ECL signal environment to a TTL signal environment. This device is designed specifically to improve the performance and density of ECL-to-TTL CPU/bus-oriented functions such as memory-address drivers, clock drivers, and bus-oriented receivers and transmitters.

Two output-enable pins,  $\overline{OE1}$  and  $\overline{OE2}$  are provided. These control inputs are ANDed together with  $\overline{OE1}$  being ECL compatible and  $\overline{OE2}$  being TTL compatible. This offers the choice of controlling the outputs of the device from either a TTL or ECL signal environment.

The SN100KT5541 is characterized for operation from 0°C to 85°C.

## logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

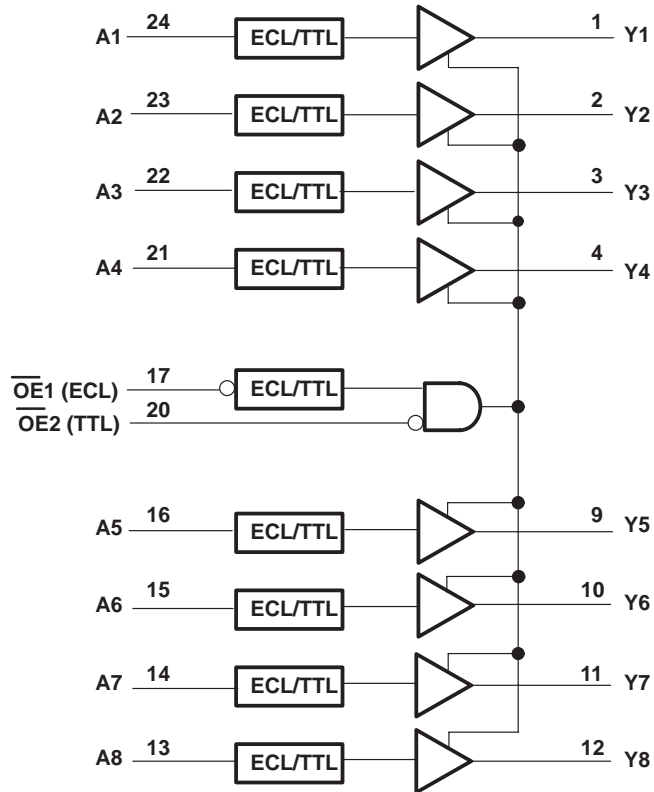
FUNCTION TABLE

OUTPUT ENABLE		DATA INPUT A	OUTPUT (TTL)
OE1	OE2		Y
X	H	X	Z
H	X	X	Z
L	L	L	L
L	L	H	H

# SN100KT5541 OCTAL ECL-TO-TTL TRANSLATOR WITH 3-STATE OUTPUTS

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logic diagram (positive logic)



**SN100KT5541**  
**OCTAL ECL-TO-TTL TRANSLATOR**  
**WITH 3-STATE OUTPUTS**

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**absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†**

Supply voltage range, $V_{CC}$ .....	–0.5 V to 7 V
Supply voltage range, $V_{EE}$ .....	–8 V to 0 V
Input voltage range (TTL) (see Note 1) .....	–1.2 V to 7 V
Input voltage range (ECL) .....	$V_{EE}$ to 0 V
Voltage applied to any output in the high state .....	–0.5 V to $V_{CC}$
Voltage applied to any output in the disabled or power-off state .....	–0.5 V to 5.5 V
Input current range (TTL) .....	–30 mA to 5 mA
Current into any output in the low state .....	96 mA
Operating free-air temperature range .....	0°C to 85°C
Storage temperature range .....	–65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The TTL input voltage ratings may be exceeded provided the input current ratings are observed.

**recommended operating conditions**

	MIN	NOM	MAX	UNIT
$V_{CC}$ TTL supply voltage	4.5	5	5.5	V
$V_{EE}$ ECL supply voltage	–4.2	–4.5	–4.8	V
$V_{IH}$ TTL high-level input voltage	2			V
$V_{IL}$ TTL low-level input voltage			0.8	V
$V_{IH}$ ECL high-level input voltage‡	–1150		–840	mV
$V_{IL}$ ECL low-level input voltage‡	–1810		–1490	mV
$I_{IK}$ TTL input clamp current			–18	mA
$I_{OH}$ High-level output current			–15	mA
$I_{OL}$ Low-level output current			48	mA
$T_A$ Operating free-air temperature	0		85	°C

‡ The algebraic convention, in which the least positive (most negative) value is designated minimum, is used in this data sheet for logic levels only.



# SN100KT5541

## OCTAL ECL-TO-TTL TRANSLATOR

### WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP†	MAX	UNIT
$V_{IK}$	OE2 only	$V_{CC} = 4.5\text{ V}$ , $V_{EE} = -4.2\text{ V}$ , $I_I = -18\text{ mA}$			-1.2	V
$I_I$	OE2 only	$V_{CC} = 5.5\text{ V}$ , $V_{EE} = -4.8\text{ V}$ , $V_I = 7\text{ V}$			0.1	mA
$I_{IH}$	OE2 only	$V_{CC} = 5.5\text{ V}$ , $V_{EE} = -4.8\text{ V}$ , $V_I = 2.7\text{ V}$			20	$\mu\text{A}$
$I_{IL}$	OE2 only	$V_{CC} = 5.5\text{ V}$ , $V_{EE} = -4.8\text{ V}$ , $V_I = 0.5\text{ V}$			-0.5	mA
$I_{IH}$	Data inputs and $\overline{\text{OE}}1$	$V_{CC} = 5.5\text{ V}$ , $V_{EE} = -4.8\text{ V}$ , $V_{IH} = -840\text{ mV}$			350	$\mu\text{A}$
$I_{IL}$	Data inputs and $\overline{\text{OE}}1$	$V_{CC} = 5.5\text{ V}$ , $V_{EE} = -4.8\text{ V}$ , $V_{IL} = -1810\text{ mV}$	0.50			$\mu\text{A}$
$V_{OH}$		$V_{CC} = 4.5\text{ V}$ , $V_{EE} = -4.5\text{ V} \pm 0.3\text{ V}$ , $I_{OH} = -3\text{ mA}$	2.4	3.3		V
		$V_{CC} = 4.5\text{ V}$ , $V_{EE} = -4.5\text{ V} \pm 0.3\text{ V}$ , $I_{OH} = -15\text{ mA}$	2	3.1		
$V_{OL}$		$V_{CC} = 4.5\text{ V}$ , $V_{EE} = -4.5\text{ V} \pm 0.3\text{ V}$ , $I_{OL} = 48\text{ mA}$		0.38	0.55	V
$I_{OZH}$		$V_{CC} = 5.5\text{ V}$ , $V_{EE} = -4.8\text{ V}$ , $V_O = 2.7\text{ V}$			50	$\mu\text{A}$
$I_{OZL}$		$V_{CC} = 5.5\text{ V}$ , $V_{EE} = -4.8\text{ V}$ , $V_O = 0.5\text{ V}$			-50	$\mu\text{A}$
$I_{OS}‡$		$V_{CC} = 5.5\text{ V}$ , $V_{EE} = -4.8\text{ V}$ , $V_O = 0\text{ V}$	-100		-225	mA
$I_{CCH}$		$V_{CC} = 5.5\text{ V}$ , $V_{EE} = -4.8\text{ V}$		64	97	mA
$I_{CCL}$		$V_{CC} = 5.5\text{ V}$ , $V_{EE} = -4.8\text{ V}$		80	120	mA
$I_{CCZ}$		$V_{CC} = 5.5\text{ V}$ , $V_{EE} = -4.8\text{ V}$		77	116	mA
$I_{EE}$		$V_{CC} = 5.5\text{ V}$ , $V_{EE} = -4.8\text{ V}$		-22	-33	mA
$C_i$		$V_{CC} = 5\text{ V}$ , $V_{EE} = 4.5\text{ V}$		5		pF
$C_o$		$V_{CC} = 5\text{ V}$ , $V_{EE} = 4.5\text{ V}$		7		pF

† All typical values are at  $V_{CC} = 5\text{ V}$ ,  $V_{EE} = -4.5\text{ V}$ ,  $T_A = 25^\circ\text{C}$ .

‡ Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (see Figure 1)

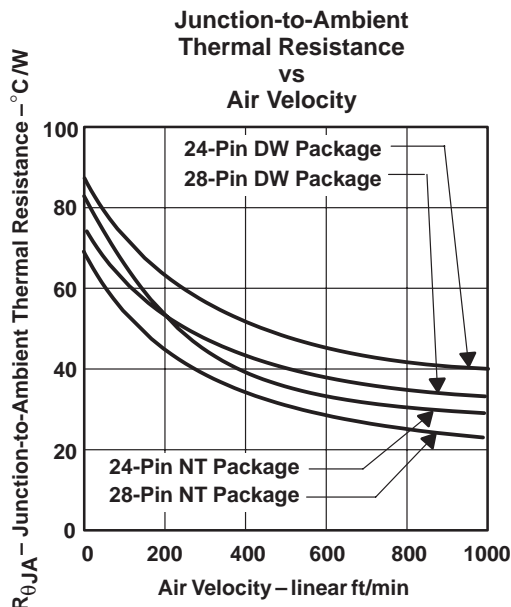
PARAMETER	FROM (INPUT)	TO (OUTPUT)	$C_L = 50\text{ pF}$ , $R_1 = 500\ \Omega$ , $R_2 = 500\ \Omega$			UNIT
			MIN	TYP§	MAX	
$t_{PLH}$	A	Y	1.7	4	6.2	ns
$t_{PHL}$			1.6	4	6.2	
$t_{PZH}$	$\overline{\text{OE}}1$	Y	2.6	4.7	6.7	ns
$t_{PZL}$			3.2	5.9	8.5	
$t_{PHZ}$	$\overline{\text{OE}}1$	Y	2.9	5.4	7.8	ns
$t_{PLZ}$			1.9	4.9	7.8	
$t_{PZH}$	$\overline{\text{OE}}2$	Y	1.7	4	6.2	ns
$t_{PZL}$			2.5	5.1	7.7	
$t_{PHZ}$	$\overline{\text{OE}}2$	Y	2.1	4.3	6.4	ns
$t_{PLZ}$			1.1	3.7	6.3	

§ All typical values are at  $V_{CC} = 5\text{ V}$ ,  $V_{EE} = -4.5\text{ V}$ ,  $T_A = 25^\circ\text{C}$ .

### THERMAL INFORMATION

In digital system designs utilizing 100KT' or 10KHT' series logic level translators, good thermal management is an important consideration for proper circuit performance and extended reliability. The size of the "small outline" package makes thermal management even more important due to the increased board and thermal densities.

The thermal resistances in Figure 1 can be used to approximate typical and maximum virtual junction temperatures for the SN100KT' and SN10KHT' translators. The junction temperature of these devices may be estimated using Equation 1.



$$T_J = R_{\theta JA} (V_{CC} \cdot I_{CC} + V_{EE} \cdot I_{EE} + P_{DRIVER}) + T_A \tag{1}$$

where

$T_J$  = virtual junction temperature

$T_A$  = ambient air temperature

$R_{\theta JA}$  = thermal resistance, junction to ambient air

$I_{CC}$  = TTL level supply current (from the databook)

$I_{EE}$  = ECL supply current

$V_{CC}$  = TTL level supply voltage (5 V for typical, 5.5 V for maximum)

$V_{EE}$  = ECL level supply voltage:

SN10KHT' – (–5.2 V Typ, –5.46 V Max)

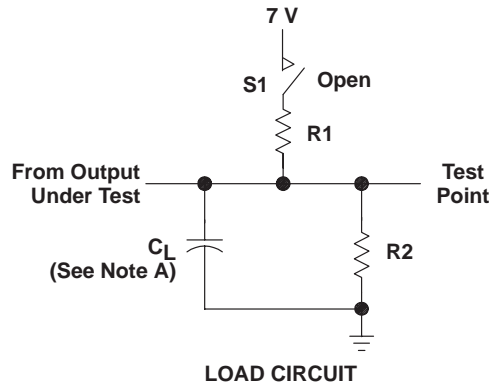
SN100KHT' – (–54.5 V Typ, –4.80 V Max)

$P_{DRIVER}$  = total power consumed by the output driver

# SN100KT5541 OCTAL ECL-TO-TTL TRANSLATOR WITH 3-STATE OUTPUTS

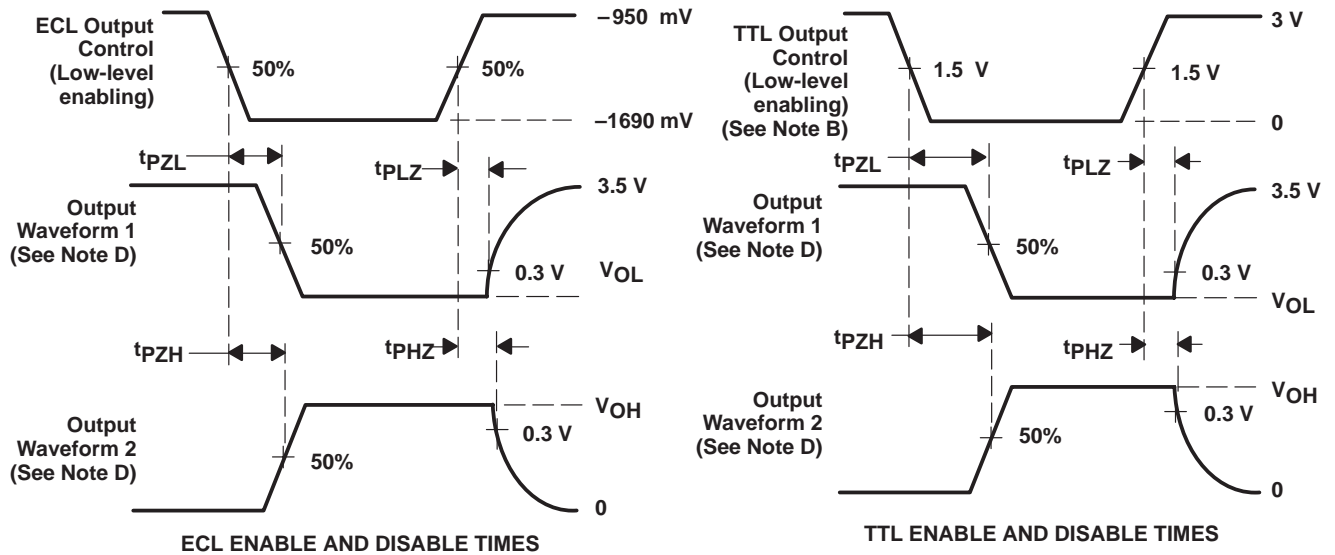
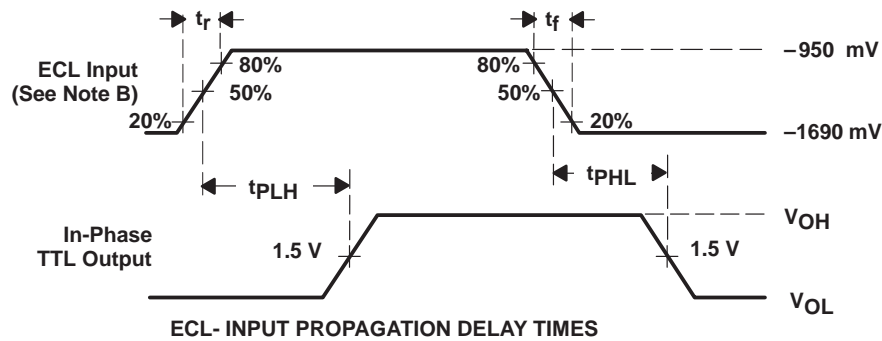
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## PARAMETER MEASUREMENT INFORMATION



**SWITCH POSITION TABLE**

TEST	S1
$t_{PLH}$	Open
$t_{PHL}$	Open
$t_{PZH}$	Open
$t_{PZL}$	Closed
$t_{PHZ}$	Open
$t_{PLZ}$	Closed



- NOTES: A.  $C_L$  includes probe and jig capacitance.  
 B. For TTL inputs, input pulses are supplied by generators having the following characteristics:  $PRR \leq 10$  MHz,  $Z_0 = 50 \Omega$ ,  $t_r \leq 2.5$  ns,  $t_f \leq 2.5$  ns.  
 C. For ECL inputs, input pulses are supplied by generators having the following characteristics:  $PRR \leq 10$  MHz,  $Z_0 = 50 \Omega$ ,  $t_r \leq 1.5$  ns,  $t_f \leq 1.5$  ns.  
 D. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.  
 E. The outputs are measured one at a time with one transition per measurement.

**Figure 1. Load Circuit and Voltage Waveforms**

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